

SBC-656 Environment Test Report

Release Date: Oct. 19, 1999

Issue Stamp QA Manager QE Manager Test Engineer

Model Name: SBC-656

Test Date : 99-10-15

Test Site: AAEON QE Dept.

Performed by: George Hsin

Test Standard:

Select	NO.	Description	
$\sqrt{}$	IEC 68-2-30	Test DB: Damp Heat Test	
$\sqrt{}$	IEC 68-2-61	Test Z/ABD : Climatic Sequence Test	

Testing Item:

Temperature & Humidity Cycle

Test Temperature & Humidity Power On/Off Test

Additional Test Peripheral:

Configuration	Model	
Test Software	QAPluse/FE V5.29	
Test Fixture	Power on/off(110V) Fixture	

Testing Equipment:

Programmable Temperature & Humidity Chamber

Model: Ths-D4L+-100

S/N: 1241

Date of Calibration: 07-10-1998

Sample Configuration & Quantity Under Test:

Use PCM-656 All-in-One Socket 370 Single Board with the following options installed.

1.CPU: Celeron 400MHz

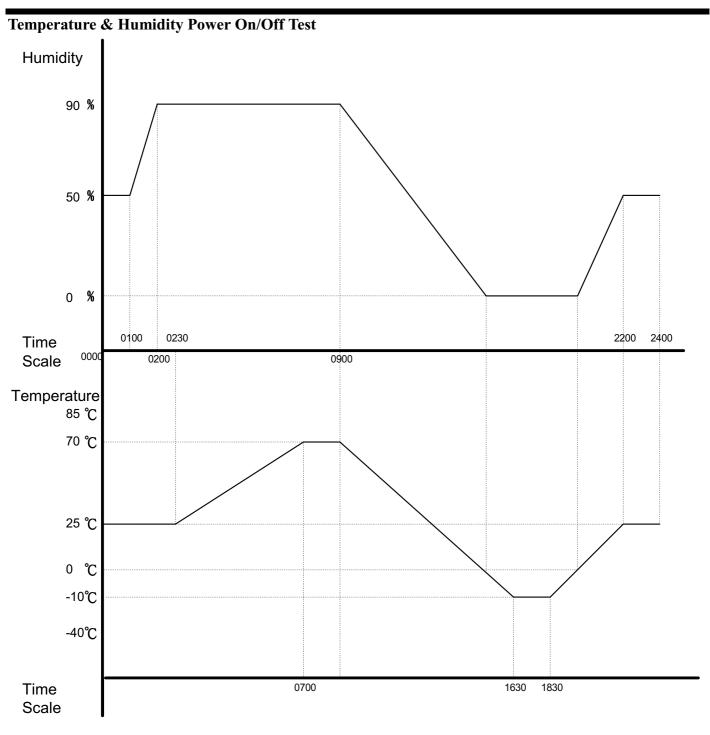
2.DRAM: 32MB(D4516821AG5-A10-9NF PC-100)

3.Chipset: Intel 440BX

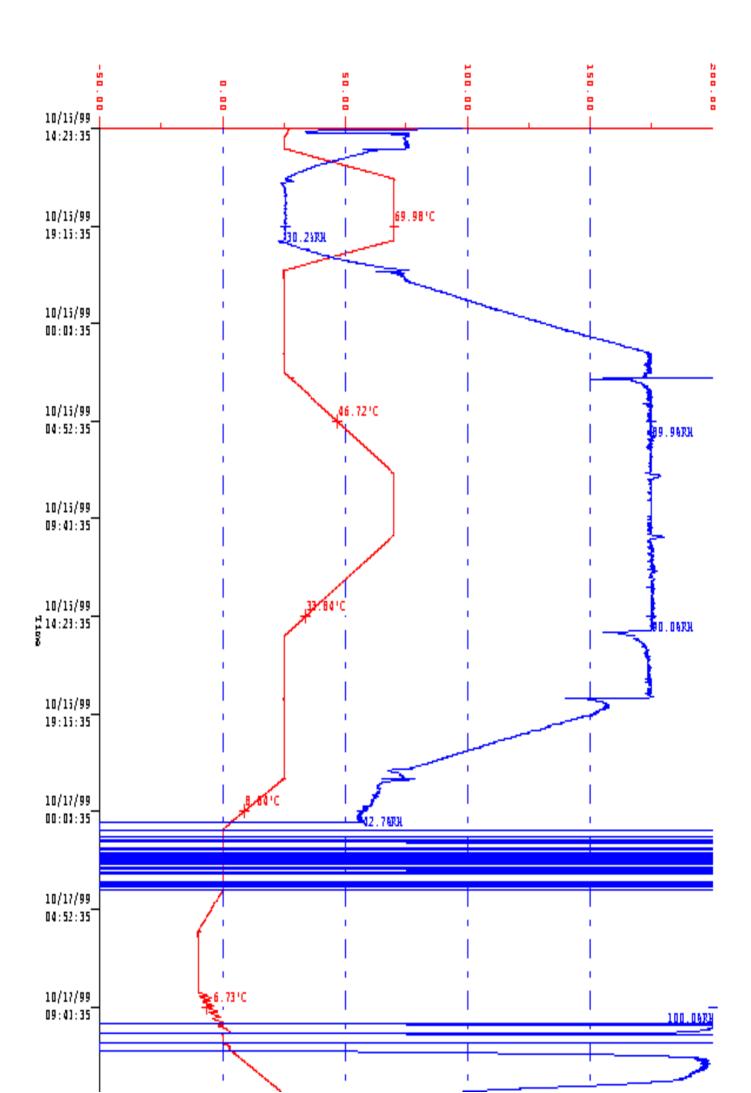
4.VGA Chipset: C&T B69000 5.I/O Chipset: Winbond W83977TF

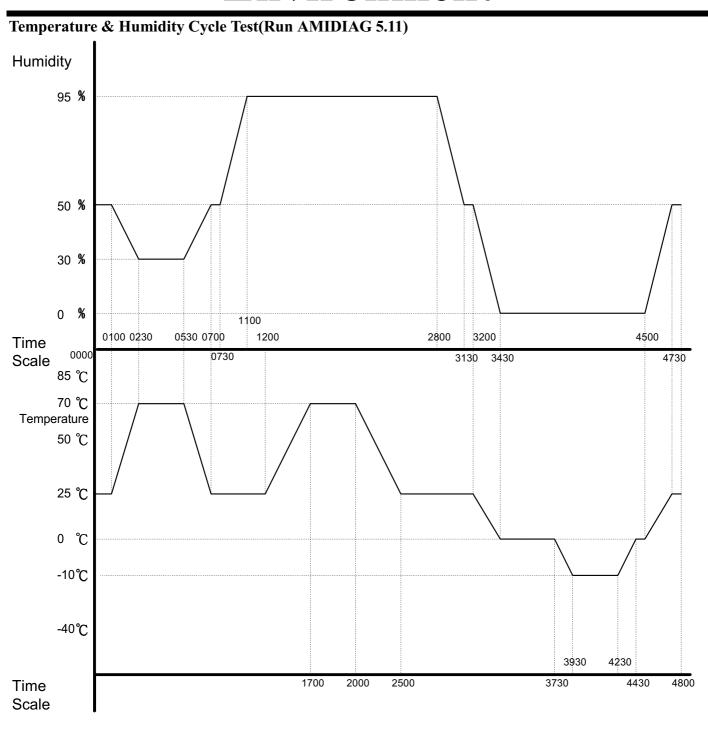
Test Result:

Standard	Description	Result
IEC 68-2-30	Temperature & Humidity Power On/Off Test	Pass
IEC 68-2-61	Temperature&HumidityCycle Test(Run QAPluse/FE V5.29)	Pass



Temperature & Humidity Power On/Off Test





Temperature & Humidity Cycle Test(Run AMIDIAG 5.11)

